



Real-World Implementation Of Semiconductors 8x8 SRAM

Using tsmc180nm CMOS technology **Circuit Level

Represented by

- Ahmed Mohamed Ahmed Hussien Mohamed
- Abdelrahman Ahmed Sheded
- Mahmoud Mohamed Abdelhamid Azazi
- Omar Ali Mohamed El Telbany
- Ahmed Mohamed Abd El Montasser
- Ahmed Mohammed Moussa Ali
- Mohamed Reda El Sayed Mohamed Shaheen

SUPERVISORS

DR/ ALSHIMAA NABIL

DR/ HOWIDA ABDELHALYM

ECE DEPARTMENT - FACULTY OF ENGINEERING

ZAGAZIG UNIVERSITY

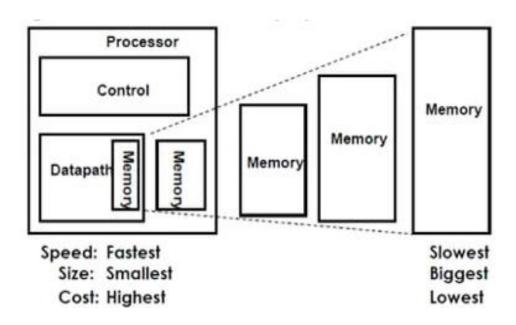
Literature Review:

Paper	Technology	Cell Size	Power Dissipation	Propagation Delay	Analysis & Tools	Advantages	Disadvantages
<u>1</u>	0.25u SCMOS	6.5um x 6.5um	0.5mW (read), 0.8mW (write)	1.2ns (read), 1.8ns (write)	HSPICE simulation, Microwind layout tool	High density, low power consumption, high speed	High leakage current, low noise margin
<u>2</u>	65nm CMOS	0.8um x 0.8um	0.4mW (read), 0.6mW (write)	1ns (read), 1.5ns (write)	Cadence Virtuoso tool, Spectre simulator	Compact size, low power consumption, high speed	High leakage current, low noise margin
<u>3</u>	180nm CMOS	3um x 3um	0.3mW (read), 0.4mW (write)	1ns (read), 1.5ns (write)	Tanner EDA tool, SPICE simulator	Low power consumption, high speed, improved stability	Large cell size, high leakage current
[4]	45nm CMOS	Not given	Not given	Not given	HSPICE simulation, Microwind layout tool	Low power consumption, high speed, reduced leakage current	Not given
[5]	180nm cmos	Not given	U.C 131uw (write)	0.47ns(Read) 0.96ns(write)	HSPICE simulation, Microwind layout tool	Low power consumption, high speed, improved stability and reliability	Not given
[6]	Not given	Not given	Not given	Not given	HSPICE simulation, Cadence layout tool	Low power consumption, high speed, improved stability and reliability, variability tolerance and low-voltage operation	
[7]	130nm RRAM-CMOS hybrid technology	Not given	Not given	Not given	Cadence Virtuoso tool, Spectre simulator	Non-volatility, low power consumption, high speed, improved stability and reliability	Larger cell size than conventional SRAM
Our work	TSMC 180NM	Not given	120 uW for 8*8 (W)	W: 839 ps , R:691 ps	Cadence Virtuoso simulator	low power, stable read and write conditions	low speed , moderate area

Storage Types:

- Volatile → DRAM & SRAM
- Non-volatile → Magnetic Storage(HDD), solid state device (SSD) and FLASH MEMORY.



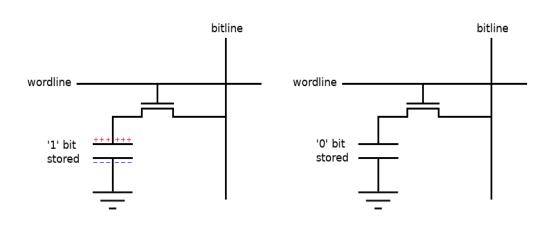




RAM types:

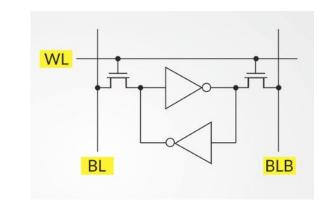
DRAM

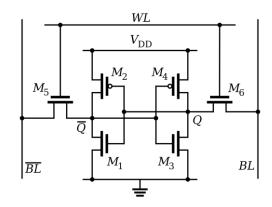
- Charge determine the stored bit (0,1)
- require periodic refresh cycle to maintain stored data.



SRAM

- Hold data without external refresh
- Simplicity: don't require external refresh circuitry
- Speed: SRAM is faster than DRAM
- Cost: several times more expensive than DRAMs
- Size: take up much more space than DRAMs
- Power: consume more power than DRAMs
- Usage: level 1 or level 2 cache

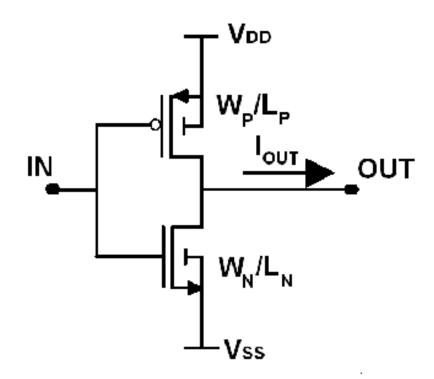


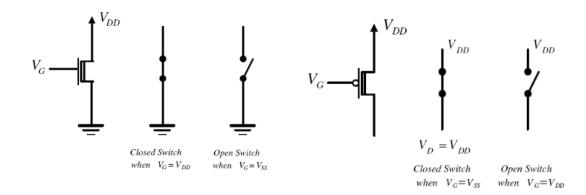


MOSFET as a switch

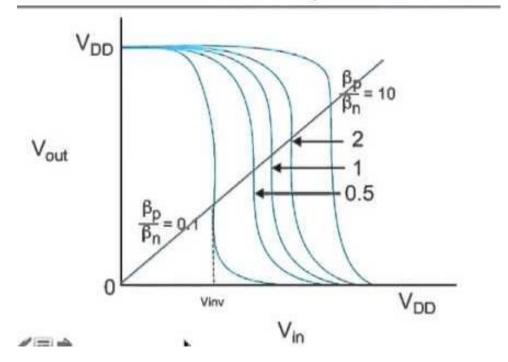
Inverter trip point

Assume WP/WN = Bp/Bn

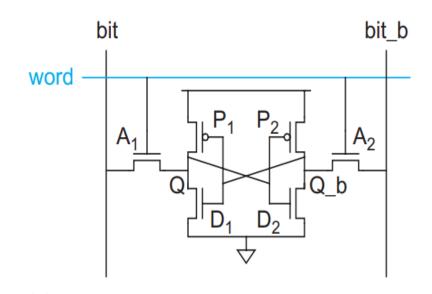




Vinv: Inverter Trip Point



How to size MOSFETS at SRAM

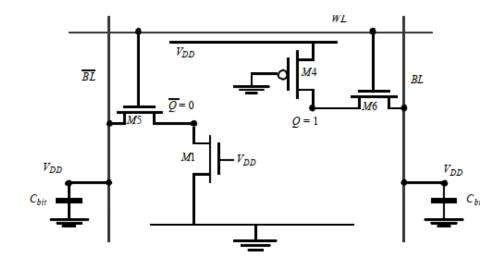


To ensure both read stability and write stability, the transistors must satisfy ratio constraints.

The NMOS pulldown transistors (D1, D2) in the cross-coupled inverters must be strongest.

The access transistors (A1,A2) are of intermediate strength, and the PMOS pullup transistors(P1,P2) must be weak. We will tell why soon.

SRAM Read Operation



Read Operation:-the value is a I, stored at Q.

The read cycle is started by pre charging both the bitlines to a logical 1, then asserting the word line WL enabling both the access transistors.

- The second step occurs when the values stored in Q and Q' are transferred to the bit lines by leaving BL at its precharged value and discharging BL through M1 and M5 to a logical O.
- On the BL side, the transistors M4 and M6 pull the bit line towards VDD, a logical 1.
- If the content of the memory was a O, the opposite would happen and BL would be pulled toward I and BL toward O.

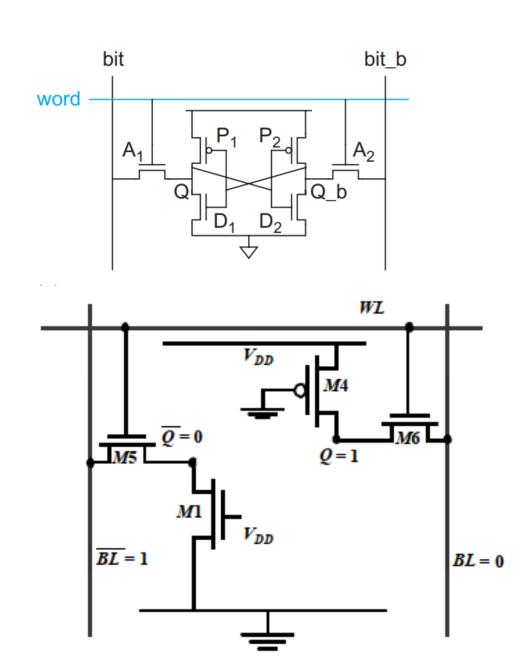
Write Operation

The start of a write cycle begins by applying the value to be written to the bit lines.

• If we wish to write a O, we would apply a O to the bit lines, i.e. setting BL' to 1 and BL to O.

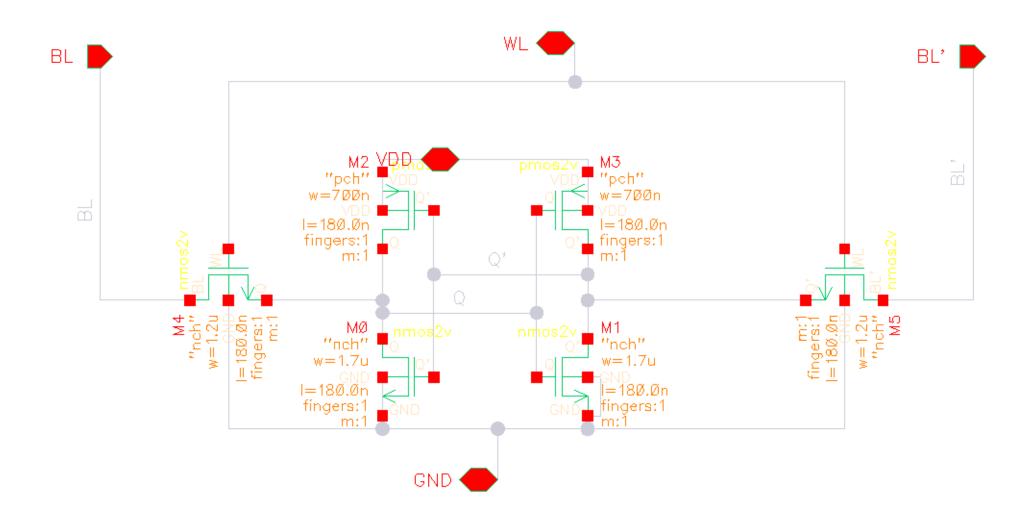
HOLD OPERATION

As long as word line is not activated the SRAM will hold is status no matter what is applied to bit line. No need for a refreshment circuit like DRAM.

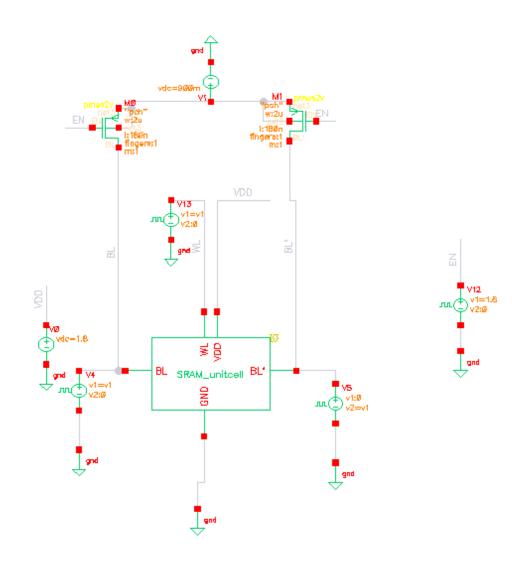


6T SRAM Circuit implementation

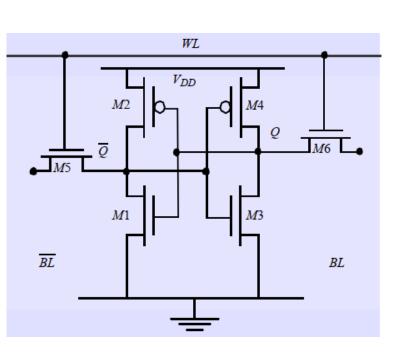
(On circuit simulator tool: CADENCE VIRTUOSO)

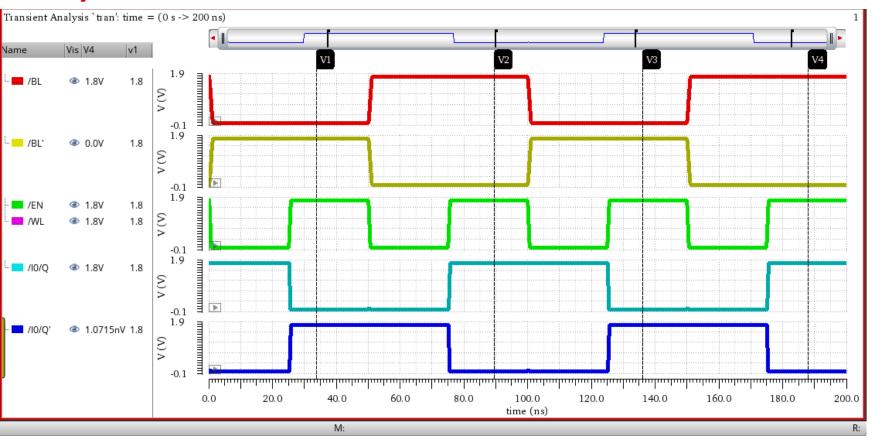


Unit cell testbench write mode

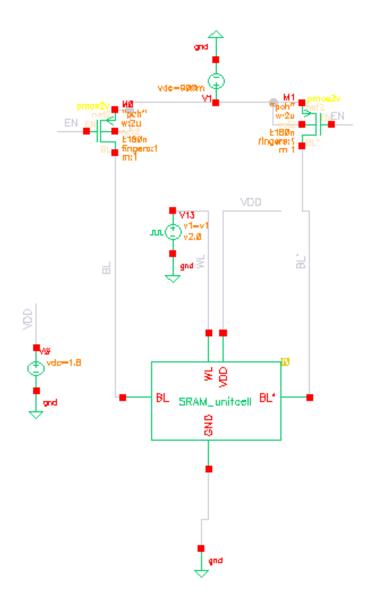


Transient analysis (write mode)



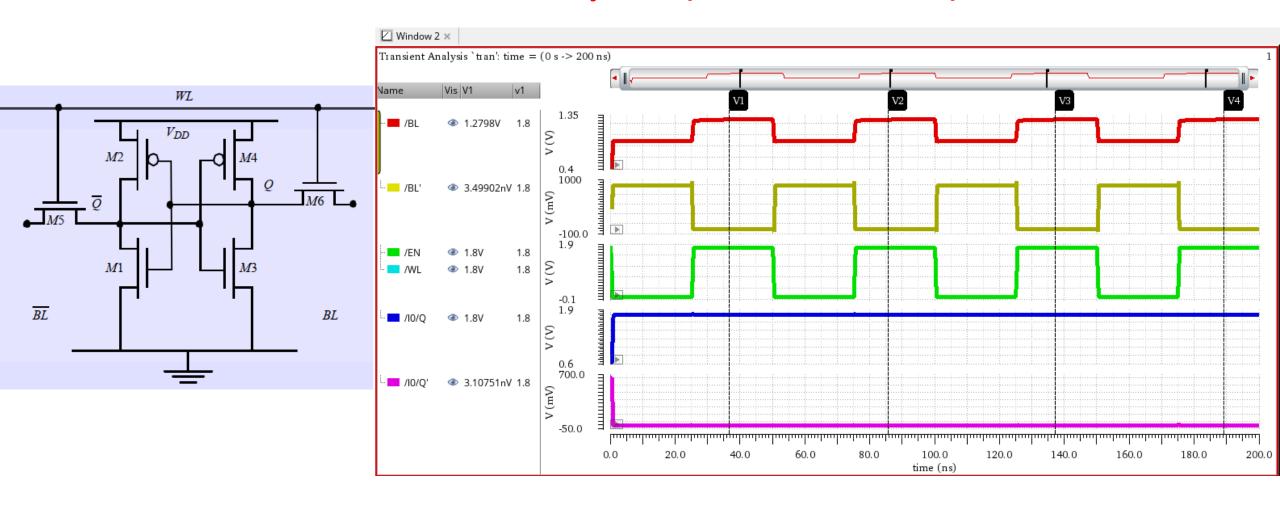


Unit cell testbench read mode





Transient analysis (read mode)



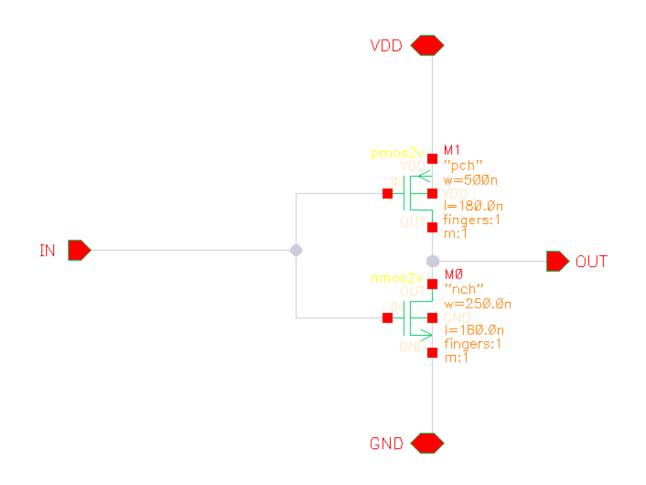
Decoder truth table

Enable	INPUTS			Outputs							
E	A ₂	A ₁	Ao	Y ₇	Y ₆	Y ₅	Y ₄	Υ ₃	Y ₂	Y ₁	Yo
0	х	х	х	0	0	0	0	0	0	0	0
1	0	0	0	0	0	0	0	0	0	0	1
1	0	0	1	0	0	0	0	0	0	1	0
1	0	1	0	0	0	0	0	0	1	0	0
1	0	1	1	0	0	0	0	1	0	0	0
1	1	0	0	0	0	0	1	0	0	0	0
1	1	0	1	0	0	1	0	0	0	0	0
1	1	1	0	0	1	0	0	0	0	0	0
1	1	1	1	1	0	0	0	0	0	0	0

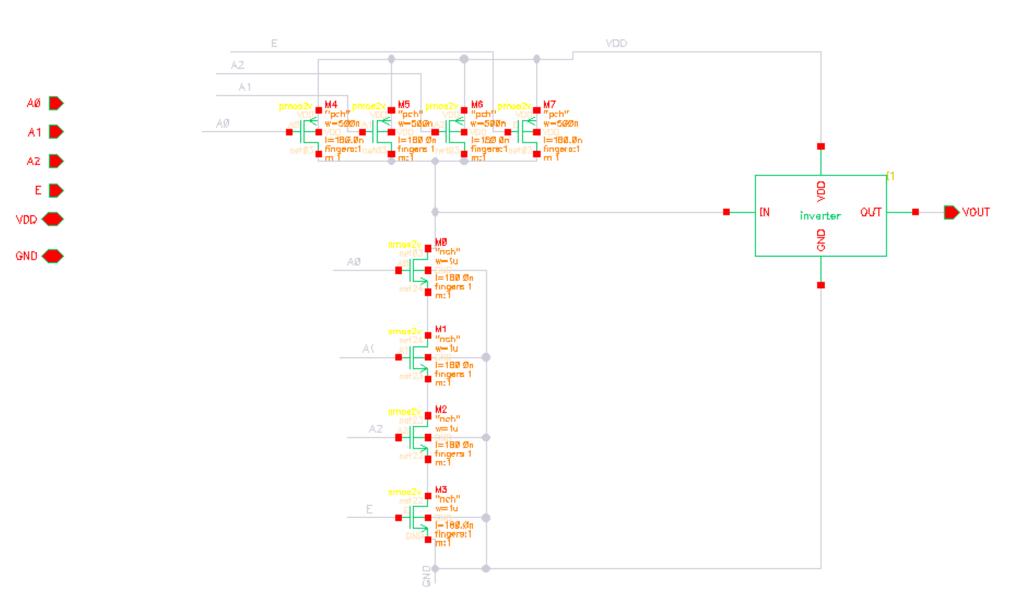
The logic expression

$$Y_0 = EN. A_0'.A_1'.A_2'$$
 $Y_1 = EN. A_0.A_1.A_2'$
 $Y_2 = EN. A_0.A_1.A_2'$
 $Y_3 = EN. A_0.A_1.A_2'$
 $Y_4 = EN. A_0'.A_1'.A_2$
 $Y_5 = EN. A_0.A_1.A_2$
 $Y_6 = EN. A_0'.A_1.A_2$
 $Y_7 = EN. A_0'.A_1.A_2$
 $Y_7 = EN. A_0.A_1.A_2$

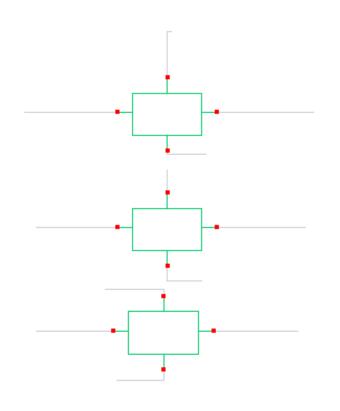
INVERTER circuit diagram

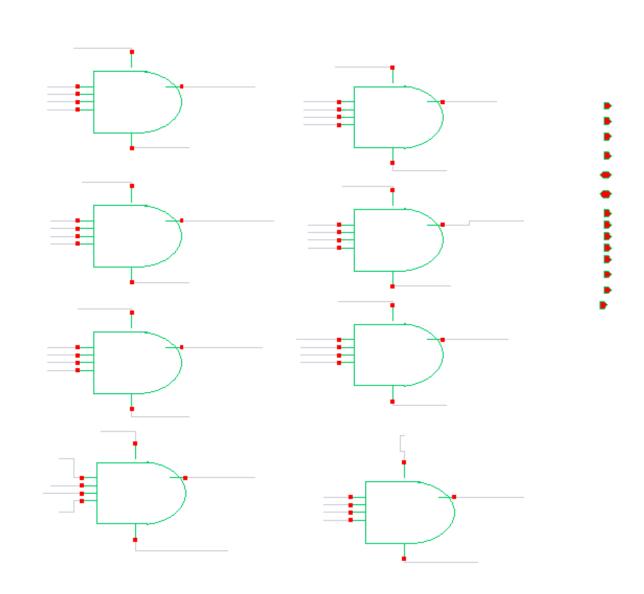


4-input AND circuit

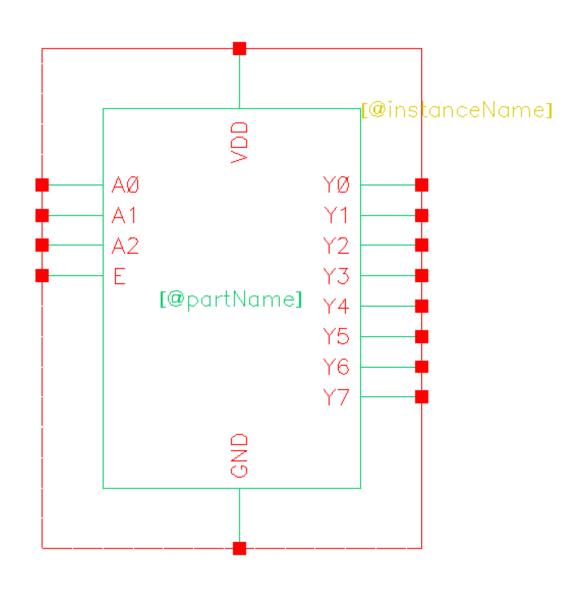


Decoder design implementation

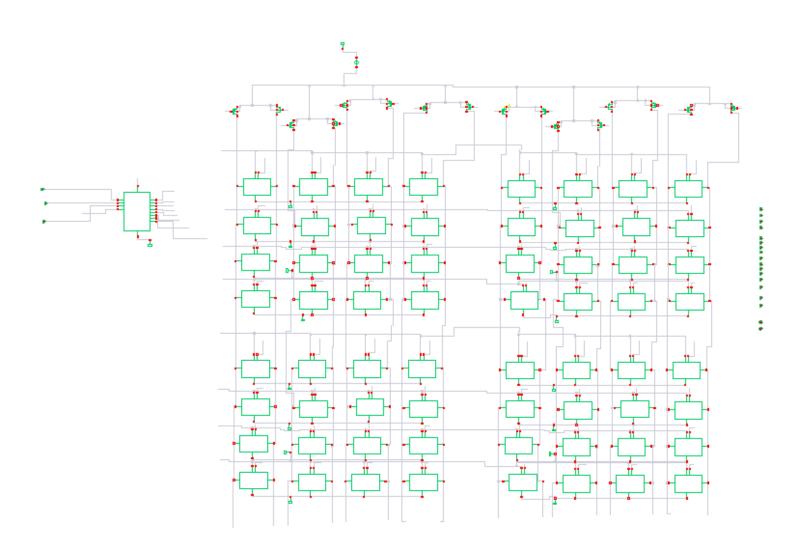




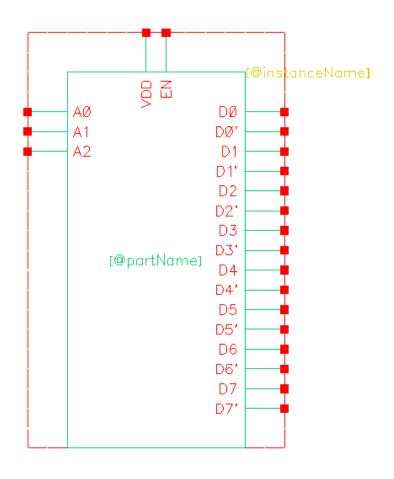
DECODER symbol



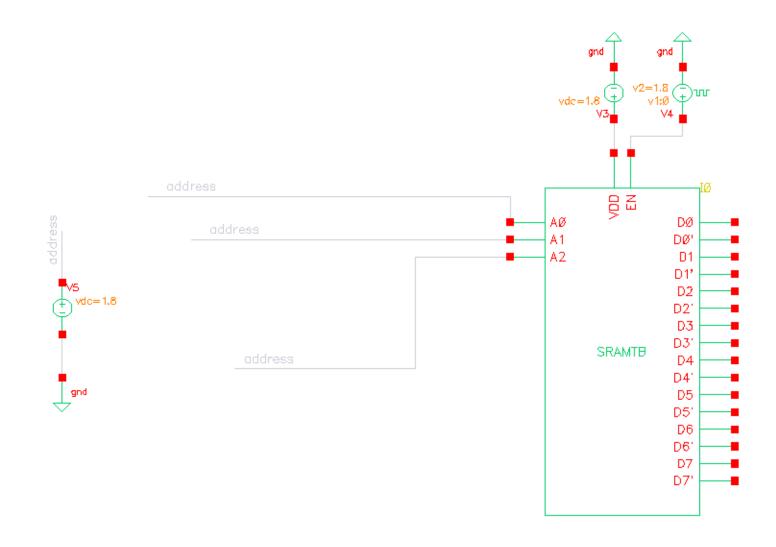
8x8 SRAM as a one unit



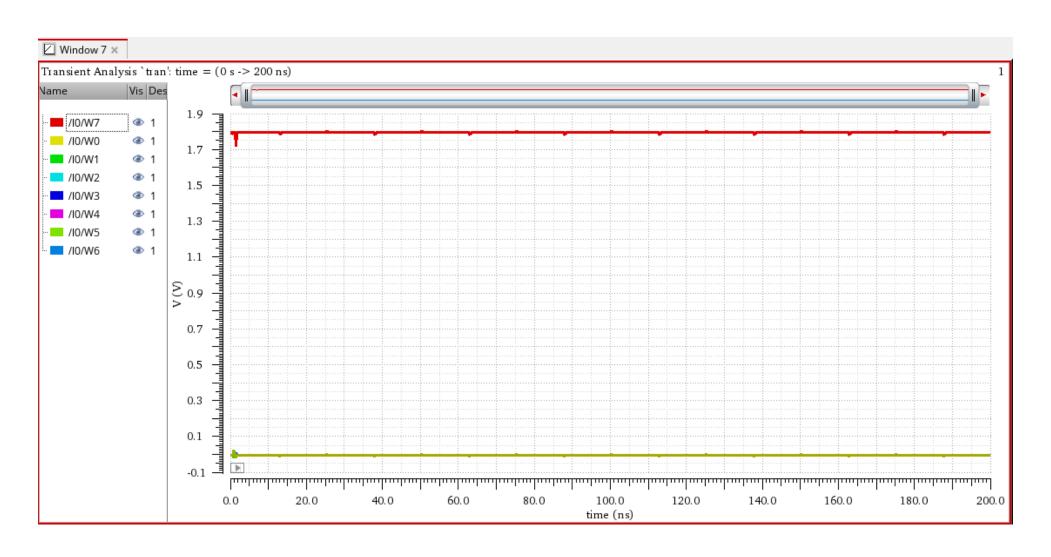
8X8 SRAM SYMBOL (as a unit chip IC)



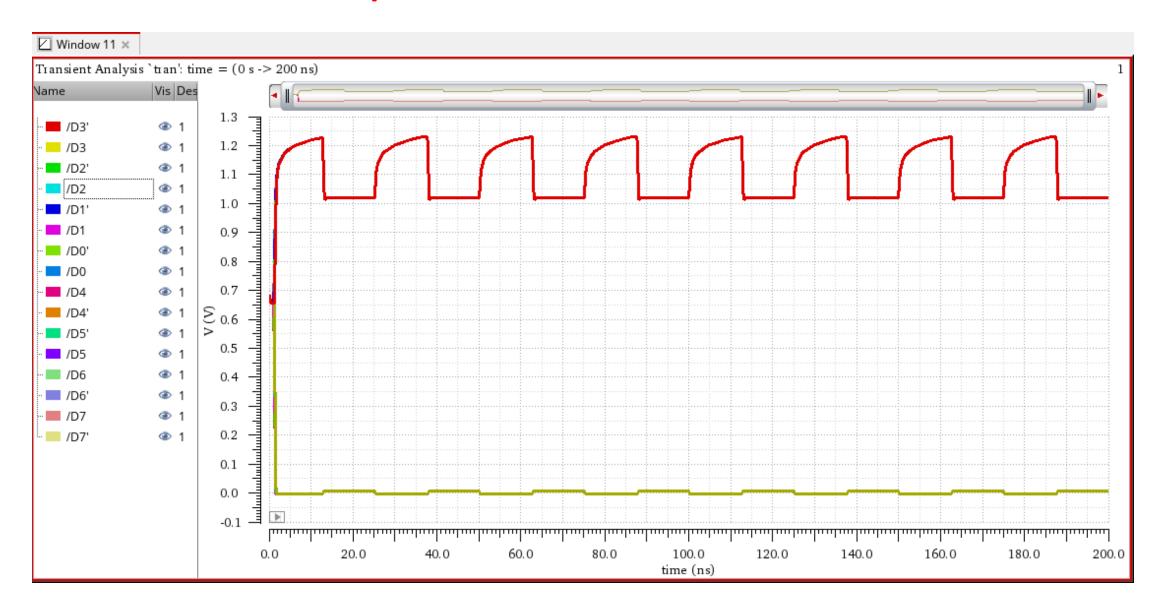
8X8 SRAM testbench

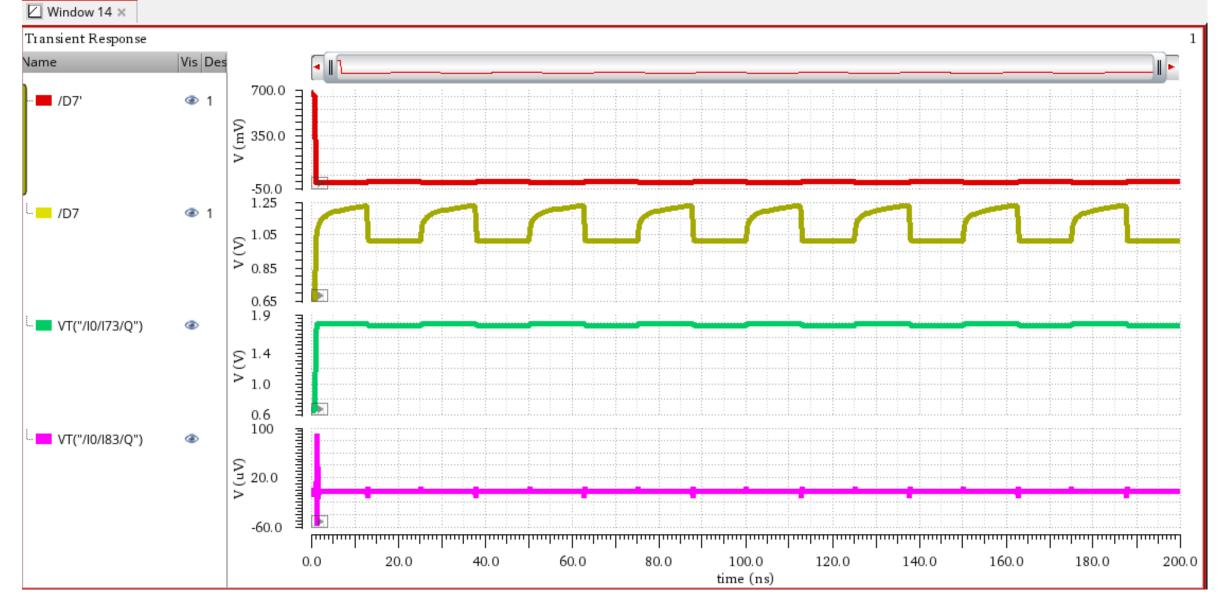


Decoder o/p (word line)



Read operation of 8x8 SRAM





**we set cell 6 to be Q=0 to make sure that the read value is correand not read from cell 6.

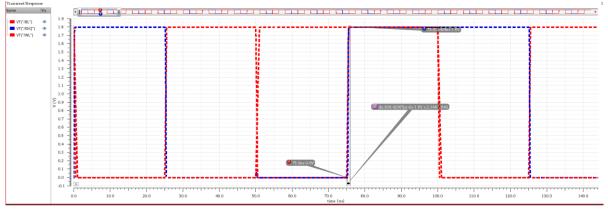
Performance check

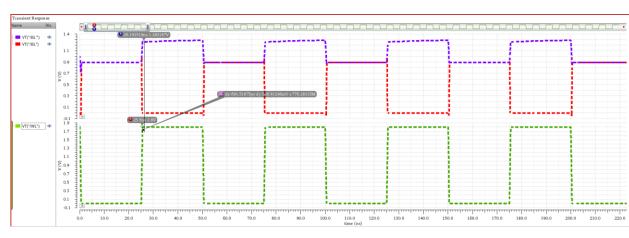
• Write delay: It is the delay between the applications of the word line WL signal and the time at which the data is actually written.

We can see the delay is actually **839.4ps**

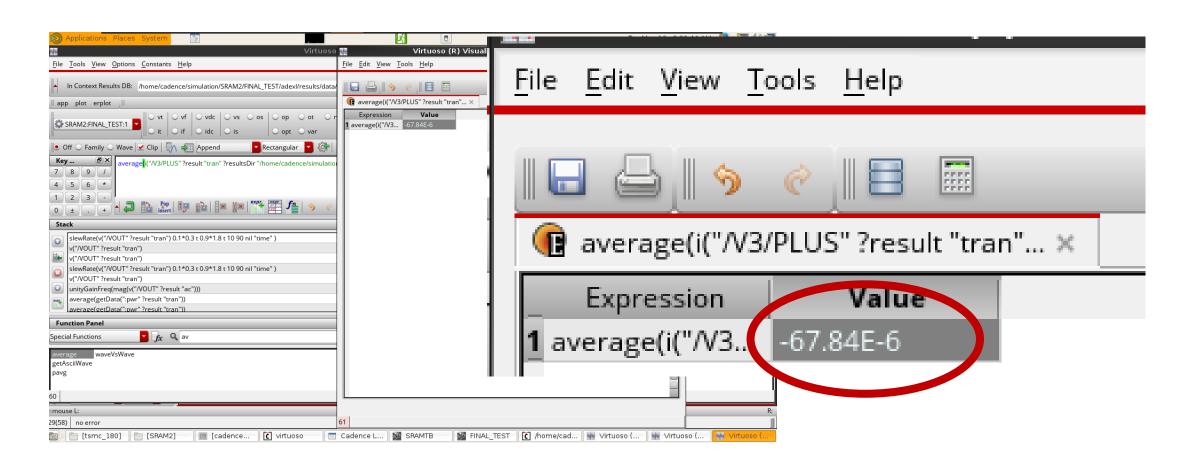
Read delay: It is the delay between the applications
of the word line WL signal and the time at which the
data is actually Read.

Read delay is about **691.6ps**





Total power dissipation I = 67.84uA, P = 120uW, @f=20Mhz



System verification through MATLAB code:

```
* Initialize the SRAM

sram = zeros(8, 8);

* Define the decoder table

* Loop until the user chooses to exit

while true

* Prompt the user to choose a read or write operation

operation = input('Enter "read" or "write" (or "exit" to quit): ', 's');

* If the user chooses to exit, break out of the loop

if strcmpi(operation, 'exit')

break;

end
```

```
* % Prompt the user to enter a binary address

address = input('Enter a 3-bit binary address (e.g. [0 1 0]): ');

% Check that the address is 3 bits long

if numel(address) ~= 3

error('Address must be 3 bits long.');

end

% Convert the binary address to a row index

row_index = bi2de(fliplr(address)) + 1;

% Perform the chosen operation

switch lower(operation)

case 'read'
```

Cont'd verification code:

```
• % Prompt the user to enter a binary address
                                                                           • % Read the data from the SRAM
     address = input('Enter a 3-bit binary address (e.g. [0 1 0]): ');
                                                                                          output_data = sram(row_index, :);
• % Check that the address is 3 bits long
     if numel(address) ~= 3
         error('Address must be 3 bits long.');
                                                                                          % Display the output data from the read operation
      end
• % Convert the binary address to a row index
                                                                                          disp('Output data from read operation:');
     row index = bi2de(fliplr(address)) + 1;
                                                                                          disp(output_data);
• % Perform the chosen operation
     switch lower(operation)
                                                                                      case 'write'
         case 'read'
```

Cont'd verification code

```
• % Prompt the user to enter data to write to the SRAM
                                                                                   • % Write the data from the user to the SRAM
              data = input('Enter 8 bits of data to write to the SRAM (e.g.
                                                                                                sram(row index, :) = data;
 [1 0 1 0 1 0 1 0]): ');
                                                                                   • % Display the SRAM contents after the write operation
                                                                                                disp('SRAM contents after write operation:');
              % Check that the data is 8 bits long
                                                                                                disp(sram);
              if numel(data) ~= 8
                                                                                            otherwise
                  error('Data must be 8 bits long.');
                                                                                                 error('Invalid operation specified.');
                                                                                         end
              end
                                                                                    end
```

Execution of the code

the Sram is set to zero as initially now we will give the Sram some words as an input (write operation)

- We can see that we select the third row from the address and we write the data using the 8_bit data line
- After making write operations to set the Sram with different values

SRAM	conte	nts	after	write	operati	ion:		
	1	1	1	1	1	1	1	1
	0	1	0	1	0	1	0	1
	1	0	1	0	1	0	1	0
	1	1	0	0	1	1	0	0
	1	1	1	1	0	0	0	0
	0	0	0	0	1	1	1	1
	0	0	1	1	0	0	1	1
	1	1	1	1	1	1	1	1

Cont'd Execution of the code

 Now if we do read operation we will select the address which will access the row and we will get 8_bit data

 If we write once again in the same address the data of the sram will updated to the new data

```
SRAM contents after write operation:
                                                            1
      O
Enter "read" or "write" (or "exit" to quit): read
Enter a 3-bit binary address (e.g. [0 1 0]): [0 1 1]
Output data from read operation:
      1
              1
                                     1
                                             1
                                                            0
Enter "read" or "write" (or "exit" to quit): write
Enter a 3-bit binary address (e.g. [0 1 0]): [0 1 1]
Enter 8 bits of data to write to the SRAM (e.g. [1 0 1 0 1 0 1 0]): [0 0 0 0 0 0 0 0]
SRAM contents after write operation:
```

FUTURE WORK!

- As we all know that we can make a larger MEMORY from smaller ones so we may built 256k more of less using this 8x8 SRAM.

- Attention!

- extending the memory size adding more the capacitance on the bit line, so we will need a **sense amplifier** to speed up the operation.

REFERENCE:

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Thanks

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